

<b>Notice of References Cited</b>	Application/Control No. 10/559,797	Applicant(s)/Patent Under Reexamination DEKKER ET AL.	
	Examiner Ralph Gitomer	Art Unit 1657	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,867,015	03-2005	Langeveld et al.	435/29
*	B	US-2006/0134725	06-2006	Langeveld, Pieter Cornelis	435/032
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	K	US-			
	L	US-			
	M	US-			

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*	N	EP 0 418 113 A2	03-1991	Israel	Reinhartz et al.	
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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